Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/680,171	TENG, TOM	
	Examiner	Art Unit	
	David E. Martinez	2181	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East see attached	12/28/2006	DM
Databases: US Patents, US PGPUBS, USOCR, EPO, JPO, Derwent, IBM_TDB.	12/28/2006	DM
710/52-61.ccls. 709/231-234.ccls. with keywords and text search	12/28/2006	DM